Issue Classification	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/751,088	KNUTH ET AL.
Examiner	Art Unit
F. Pierre VanderVegt	1644

	ISSUE CLASSIFICATION											
ORIGINAL			CROSS REFERENCE(S)									
CLASS SUBCLASS CLASS				SUBCLASS (ONE SUBCLASS PER BLOCK)								
536 23.5		536	23.1									
INTERNATIONAL CLASSIFICATION			435	325	320.1							
С	1	2	N	15/09								
С	1	2	N	15/63								
С	1	2	N	5/02								
С	0	7	Η	21/04								
			,	/								
	F. Pierre VanderVegt 5/1/06 (Assistant Examiner) (Date)				CHRISTINA CHAN SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 1600 (Primary Examiner) (Date)				Total Claims Allowed: 8			
Eaosu Smalluss (5-1-06 (Legal Instruments Examiner): (Date)				Mallword 5 uments Examiner) (Print C	Print Fig. None		

Mali	licant	☐ CPA ☐ T.D.		☐ R.1.47					
Claims renumbered in the same order as presented by applica			ilcant						
Final	Final	Final	Final	Final	Original	Final	Original	Final	Original
	3/1	6	91		121		151		181
1 2	32	62	92		122		152		182
3	33	6 B	93		123		153		183
4	34	64	40ء		124		154		184
5	35	e 5	1 95		125		155		185
6	36	6 6	2 96		126		156		186
1	. 37	6 7	3 97		127		157		187
В	38	6 8	4 98		128		158		188
\$	39	69	5 99		129		159		189
10	40	70	6 100		130		160		190
111	41	71	7 10		131		161		191
12	42	72	8 102		132		162		192
13	43	73	10.		133		163		193
14	44	74	104		134		164		194
15	45	75	10		135		165		195
16	46	76	100		136		166		196
17	47	7/7	10		137		167		197
18	48	7/8	108	3	138		168		198
	49	719	10		139		169		199
19 20 21 22 23 24	50	80 81	110		140		170		200
21	51	81	11		141		171		201
222	52	82 83 84	11:		142		172		202
23	53	83	11	<u> </u>	143		173		203
24	54	84	11	!	144		174		204
2 5 26	55	8 5	11		145		175		205
26	56	86	110		146		176		206
21	57	87	11	_	147		177		207
28	58	88	11	3	148		178		208
29	549	89	11		149		179		209
30	60	90	12) [150		180		210